

Substitute for form 1449A/PTO		Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/625,205		
		Filing Date	7/22/2003		
		First Named Inventor	Davis et al.		
		Art Unit	2621		
		Examiner Name	Not Known		
Sheet	1	of	2	Attorney Docket Number	C03-003

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Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Signature	/Kanjibhai Patel/	Date Considered	10/27/2006
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PTO/SB/08b (08-03)

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				Filing Date	7/22/2003
				First Named Inventor	Davis
				Art Unit	2621
				Examiner Name	Not Known
Sheet	2	of	2	Attorney Docket Number	C03-003

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
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Examiner Signature	/Kanjibhai Patel/	Date Considered	11/01/2006
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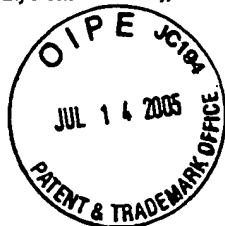
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Application Number 10/625,205

Filing Date July 22, 2003

First Named Inventor Davis, Jason

Group Art Unit Unknown

Examiner Name Unknown

Sheet 1 of 1

Attorney Docket No: C03-003

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First Named Inventor	Davis, Jason
Group Art Unit	Unknown
Examiner Name	Unknown

Sheet 1 of 1

Attorney Docket No: C03-003

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